

10/587194

IAP11 Rec'd PCT/PTO 24 JUL 2006

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

EXPRESS MAIL NO. EV827401168US

Applicant : Jean-Louis Stehle

Application No. : To be assigned

Filed : July 24, 2006

Title : PROTECTED PATTERN MASK FOR REFLECTION LITHOGRAPHY
IN THE EXTREME UV OR SOFT X-RAY RANGE

Grp./Div. : To be assigned

Examiner : To be assigned

Docket No. : 58059/N75

**INFORMATION DISCLOSURE STATEMENT
37 CFR § 1.97(b)**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Post Office Box 7068
Pasadena, CA 91109-7068
July 24, 2006

Commissioner:

In compliance with the duty of disclosure under 37 CFR §§ 1.56, 1.97 and 1.98, and in accordance with the provisions in the Manual of Patent Examining Procedure §§ 609 and 707.05(b), enclosed is FORM PTO/SB/08A/B listing the references that are known to applicant. Copies of each of the listed Foreign Patent Documents and Other Documents are enclosed. This filing is timely because it is made during one of the periods described in 37 CFR § 1.97(b).

It is respectfully requested that the listed references be considered in the examination of this application and identified on the list of references cited on the patent issuing for this application. Applicant also requests that an initialed copy of FORM PTO/SB/08A/B be entered in the application file and returned to applicant with the next communication from the Office in accordance with MPEP § 609.

10/587194
IAP11 Rec'd PCT/PTO 24 JUL 2006

Application No. To be assigned

Respectfully submitted,

CHRISTIE, PARKER & HALE, LLP

By 

D. Bruce Prout

Reg. No. 20,958

626/795-9900

DBP/mac

Enclosures: Form PTO/SB/08A/B, w/references

MAC PAS692745.1.*-07/24/06 2:03 PM

FORM PTO/SB/08A/B (10-01) Substitute for PTO-1449A/B	Attorney Docket Number	58059/N75
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)	Application Number	To be assigned
	Filing Date	July 24, 2006
	Applicant(s)	Jean-Louis Stehle
	Group Art Unit	To be assigned
	Examiner Name	To be assigned

U.S. PATENT DOCUMENTS				
EXAMINER INITIALS	Cite No. ¹	DOCUMENT NUMBER Number - Kind Code ² (If Known)	Publication Date MM-DD-YYYY	Name of Patentee
		5,474,865	12-12-1995	Vasudev
		6,280,886	08-28-2001	Yan
		2002/0018941 A1	02-14-2002	Matsumoto et al.
		6,492,067 B1	12-10-2002	Klebanoff et al.
		6,623,893 B1	09-23-2003	Levinson et al.

FOREIGN PATENT DOCUMENTS					
EXAMINER INITIALS	Cite No. ¹	FOREIGN PATENT DOCUMENT Country Code ³ - Number ⁴ - Kind Code ⁵ (If Known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	T ⁶ (✓)
		WO 03/096121 A2	11-20-2003	Thony et al.	English abstract

OTHER DOCUMENTS		
EXAMINER INITIALS	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
		Maldonado, J.R., et al., Pellicles for X-Ray Lithography Masks, Etec Systems, Inc., SPIE Vol. 3331, pgs. 245-254
		International Search Report, dated January 3, 2006, Corresponding to PCT/FR2005/000168

MAC PAS692748.1-*07/24/06 3:03 PM

EXAMINER SIGNATURE		DATE CONSIDERED	
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.pto.gov or MPEP 901.4. ³ Enter Office that issued the document, by the two-letter code (WIPO standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English Language Translation is attached.			